Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and I ${ }^{2}$ C Interface

## General Description

The MAX20067/MAX20067B are complete TFT bias solutions for automotive applications. They include a currentmode boost converter and two push-pull charge-pump drivers.

The ICs also include a gate-shading push-pull level shifter that can be used to improve display uniformity (when needed), and a DAC and VCOM buffer. All blocks on the ICs can be used in stand-alone mode or through the $I^{2} \mathrm{C}$ interface.
Comprehensive control functions are included using the built-in $I^{2} \mathrm{C}$ interface, as well as diagnostics and monitoring.
The ICs are intended to operate with 2.7 V to 5.5 V supplies.
The MAX20067/MAX20067B are available in a 32-pin TQFN package and operate in the $-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$ temperature range.

## Applications

- Infotainment Displays
- Central Information Displays
- Instrument Clusters


## Benefits and Features

- Versatile TFT Display Power Section
- Integrated Synchronous Boost Converter with Output Voltages Up to 18 V and High-power (MAX20067) or Lower-power (MAX20067B) Options
- Integrated Charge-Pump Drivers for the VGON ( +32 V , max) and VGOFF ( -24 V , min) Outputs
- Low EMI Operation
- Programmable Switching Frequencies of 440 kHz or 2.2MHz
- Programmable Spread Spectrum
- Full Sequencing Flexibility Through $I^{2} \mathrm{C}$, Along with Preset Sequences Using SEQ Pin
- Extended Diagnostics Using I ${ }^{2} \mathrm{C}$ Interface
- Undervoltage/Overvoltage on HVINP, VGON, and VGOFF
- Overcurrent on AVDD
- Temperature Warning
- Built-In Gate-Shading Circuit Controlled by CTL Input
- 8-Bit DAC-Controlled VCOM Buffer
- Robust
- $-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$ Operating Temperature Range
- Internal Temperature Shutdown
- AEC-Q100 Qualified
- Compact 32-Pin ( $5 \mathrm{~mm} \times 5 \mathrm{~mm}$ ) TQFN Package

Ordering Information appears at end of datasheet.


## MAX20067/MAX20067B

## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

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## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $\mathrm{I}^{2} \mathrm{C}$ Interface

## Absolute Maximum Ratings

INA, SDA, SCL, ENP, FLTB, CTL to GND ............... -0.3 V to +6 V
DEL, REF, FBP, FBGH, FBGL, SEQ, MODE, ADD to GND ...... 0.3 V to $\mathrm{INA}+0.3 \mathrm{~V}$

LXP, BST to GND.................................................... - 0.3 V to 26 V
BST to LXP.............................................................. 0.3 V to +6 V
HVINP, VCOMP to GND ....................................... - 0.3 V to +26 V
VCINH, VCOM to GND............................ -0.3 V to $\mathrm{V}_{\mathrm{COMP}}+0.3 \mathrm{~V}$
VCINH to VCOM..................................................................... 1 V
AVDD, PGVDD to HVINP......................... 0.3 V to HVINP + 0.3 V
VGON, SRC, DRN to GND.................................... - 0.3 V to +34 V
DRN to GATES....................................................... 34 V to +34 V
GATES to GND ...........................................-0.3V to SRC + 0.3V
VGOFF to GND ..................................................... -26V to +0.3V

DRVP, DRVN to PGND ............................-0.3V to HVINP + 0.3V
GND to PGND.......................................................-0.3V to +0.3V
GND to DGND ......................................................-0.3V to +0.3V
LXP Continuous Current.......................................................2.4A
Continuous Power Dissipation (Multilayer Board) ( $\mathrm{T}_{\mathrm{A}}=+70^{\circ} \mathrm{C}$ )...
W to 2.758 W
Package Thermal Resistance ......................................... $1.7^{\circ} \mathrm{C} / \mathrm{W}$
ESDHB..................................................................... 2 kV to +2 kV
ESDMM...............................................................-200V to +200V
Operating Temperature........................................ $40^{\circ} \mathrm{C}$ to $105^{\circ} \mathrm{C}$
Junction Temperature ......................................... $40^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Storage Temperature Range .............................. $65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Lead Temperature Range ................................................ $+300^{\circ} \mathrm{C}$
Note 1: Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a 4-layer board. For detailed information on package thermal considerations see www.maximintegrated.com/thermal-tutorial.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## Package Information

## 32-Pin TQFN

| Package Code | T3255+4C |
| :--- | :--- |
| Outline Number | $\underline{21-0140}$ |
| Land Pattern Number | $\underline{90-0012}$ |
| Thermal Resistance, Single-Layer Board: |  |
| Junction to Ambient $\left(\theta_{\mathrm{JA}}\right)$ | 47 |
| Junction to Case $\left(\theta_{\mathrm{JC}}\right)$ | 1.7 |
| Thermal Resistance, Four-Layer Board: |  |
| Junction to Ambient $\left(\theta_{\mathrm{JA}}\right)$ | 29 |
| Junction to Case $\left(\theta_{\mathrm{JC}}\right)$ | 1.7 |

For the latest package outline information and land patterns (footprints), go to www.maximintegrated.com/packages. Note that a " + ", "\#", or "-" in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status.
Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a four-layer board. For detailed information on package thermal considerations, refer to www.maximintegrated. com/thermal-tutorial.

## Electrical Characteristics

$\left(\mathrm{V}_{\text {INA }}=3.6 \mathrm{~V}\right.$, Limits are $100 \%$ tested at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ and $\mathrm{T}_{\mathrm{A}}=+105^{\circ} \mathrm{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested. $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{J}}=-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: |
| INA POWER INPUT | $V_{\text {INA }}$ |  | 2.7 | 5.5 | V |  |
| INA Supply Voltage <br> Range | UVLO $_{\text {R }}$ |  | 2.45 | 2.55 | 2.65 | V |
| INA Undervoltage- <br> Lockout Threshold, <br> Rising |  |  |  |  |  |  |

Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Electrical Characteristics (continued)

$\left(\mathrm{V}_{\text {INA }}=3.6 \mathrm{~V}\right.$, Limits are $100 \%$ tested at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ and $\mathrm{T}_{\mathrm{A}}=+105^{\circ} \mathrm{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested. $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{J}}=-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| INA UndervoltageLockout Threshold, Falling | UVLOF |  |  | 2.45 |  | V |
| Supply Current | IINA | ENP = 1 or ENP bit = 1, no switching |  | 1.8 | 3 | mA |
| Shutdown Current | ISD | ENP $=0$ and ENP bit $=0$, total current INA + HVINP |  | 7 | 15 | $\mu \mathrm{A}$ |
| OSCILLATOR |  |  |  |  |  |  |
| Boost Converter Switching Frequency | fswo | SWFREQ bit $=0$ | 1.98 | 2.2 | 2.42 | MHz |
| Boost Converter Switching Frequency, Low Setting | fsw1 | SWFREQ bit = 1 | 390 | 440 | 490 | kHz |
| Frequency Dither |  | SSOFF bit = 1 | -4 |  | +4 | \% |
| REFERENCE |  |  |  |  |  |  |
| REF Output Voltage | $\mathrm{V}_{\text {REF }}$ |  | 1.238 | 1.25 | 1.262 | V |
| REF Load Regulation |  | $\mathrm{I}_{\text {REF }}$ from $0 \mu \mathrm{~A}$ to $100 \mu \mathrm{~A}$ |  | 10 | 20 | mV |
| REF Line Regulation |  | $2.7 \mathrm{~V}<\mathrm{V}_{\text {INA }}<5.5 \mathrm{~V}$, no load |  |  | 5 | mV |
| BOOST CONVERTER |  |  |  |  |  |  |
| AVDD Output Voltage Range | $\mathrm{V}_{\text {AVDD }}$ |  | $\mathrm{V}_{\text {INA }}+1$ |  | 18 | V |
| LXP Current Limit |  | MAX20067B, 75\% duty-cycle | 0.75 | 1 | 1.25 | A |
|  |  | MAX20067, 85\% duty cycle | 2.1 | 2.5 | 2.9 |  |
| Low-Side Switch OnResistance | RLXP |  |  | 0.2 | 0.4 | $\Omega$ |
| LXP Leakage Current | ILXP | $\mathrm{V}_{\mathrm{LXP}}=18 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ |  |  | 5 | $\mu \mathrm{A}$ |
| Synchronous Rectifier On-Resistance | $\mathrm{R}_{\text {SYNC }}$ |  |  | 0.25 | 0.5 | $\Omega$ |
| Synchronous Rectifier <br> Zero-Crossing <br> Threshold | ISYNCZ | 2.2 MHz |  | 140 |  | mA |
| Maximum Duty Cycle | DC MAX |  | 90 | 94 | 98 | \% |
| Current-Limit Ramp Time at Startup | $t_{\text {RAMP }}$ |  |  | 12.5 |  | ms |
| FBP Regulation Voltage | $\mathrm{V}_{\text {FPB }}$ |  | 1.225 | 1.25 | 1.275 | V |
| FBP Load Regulation |  | $1 \mathrm{~mA}<\mathrm{I}_{\text {AVDD }}<200 \mathrm{~mA}$ |  | -1 |  | \% |
| FBP Line Regulation |  | $\mathrm{V}_{\text {INA }}=2.7 \mathrm{~V}$ to 5.5 V | -0.4 |  | +0.4 | \% |
| FBP Undervoltage-Fault Threshold | $V_{\text {FBPUV }}$ |  | 75 | 80 | 85 | \% |
| FBP Overvoltage-Fault Threshold | $\mathrm{V}_{\text {FBPOV }}$ |  | 110 | 115 | 120 | \% |

## Electrical Characteristics (continued)

$\left(\mathrm{V}_{\text {INA }}=3.6 \mathrm{~V}\right.$, Limits are $100 \%$ tested at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ and $\mathrm{T}_{\mathrm{A}}=+105^{\circ} \mathrm{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested. $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{J}=-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| FBP Input Bias Current | $\mathrm{I}_{\text {FBP }}$ |  |  |  | 200 | nA |
| HVINP-AVDD Switch On-Resistance | $\mathrm{R}_{\mathrm{HA}}$ |  |  | 0.5 | 1 | $\Omega$ |
| AVDD Discharge Resistance | $\mathrm{R}_{\text {AVDD }}$ |  | 1 | 1.5 | 2 | k $\Omega$ |
| HVINP-AVDD Switch Current Limit | ILIMHA | After soft-start | 240 |  |  | mA |
|  |  | During soft-start | 120 |  |  |  |

POSITIVE CHARGE-PUMP REGULATOR


NEGATIVE CHARGE-PUMP REGULATOR

| VGOFF Output Voltage Range |  |  | -24 |  | -4 | V |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| DRVN Current Limit | ILIMN |  | 15 |  |  | mA |
| Negative Charge-Pump Switching Frequency |  |  | 440 |  |  | kHz |
| FBGL Regulation Voltage | $\mathrm{V}_{\text {FBGL }}$ | $\mathrm{V}_{\text {REF }}-\mathrm{V}_{\text {FBGL }}$ | 0.98 | 1 | 1.02 | V |
| FBGL UndervoltageFault Threshold | V ${ }_{\text {FBGLUV }}$ | Rising | 400 | 450 | 500 | mV |

## Electrical Characteristics (continued)

$\left(\mathrm{V}_{\text {INA }}=3.6 \mathrm{~V}\right.$, Limits are $100 \%$ tested at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ and $\mathrm{T}_{\mathrm{A}}=+105^{\circ} \mathrm{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested. $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{J}}=-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| FBGL Overvoltage-Fault Threshold | $V_{\text {FBGLOV }}$ | Falling | 20 | 50 | 100 | mV |
| DRVN On-Resistance High | RONH_DRVN |  |  |  | 60 | $\Omega$ |
| DRVN On-Resistance Low |  |  |  |  | 30 | $\Omega$ |
| VGOFF Discharge Resistance |  |  | 8 | 12 | 16 | k $\Omega$ |
| GATE-SHADING CIRCUIT |  |  |  |  |  |  |
| SRC Input Voltage Range | $\mathrm{V}_{\text {SRC }}$ |  |  |  | 32 | V |
| SRC-to-GATES Switch On-Resistance | RSRC_GATES |  |  | 10 | 20 | $\Omega$ |
| DRN-to-GATES Switch On-Resistance | RDRN_GATES |  |  | 10 | 20 | $\Omega$ |
| DEL Pullup Current |  |  | 4 | 5 | 6 | $\mu \mathrm{A}$ |
| DEL Enable Threshold |  |  |  | 1.25 |  | V |
| CTL-to-GATES Delay |  | $\mathrm{C}_{\text {GATES }}=1 \mathrm{nF}$ |  | 150 |  | ns |
| MODE Switch OnResistance |  |  |  | 1250 |  | $\Omega$ |
| MODE Voltage Threshold |  | MODE rising | 2 |  |  | V |
| MODE Pullup Current |  |  | 80 | 100 | 120 | $\mu \mathrm{A}$ |
| MODE Current-Source Stop Threshold |  |  |  | 1.7 |  | V |
| VCOM BUFFER |  |  |  |  |  |  |
| VCOMP Voltage Range |  |  | 5 |  | 18 | V |
| VCOMP Quiescent Supply Current |  | $\mathrm{I}_{\mathrm{VCOMP}}=0 \mathrm{~mA}, \mathrm{~V}_{\text {COMP }}=12 \mathrm{~V}$ |  | 1.8 |  | mA |
| VCINH Input Impedance |  |  |  | 500 |  | $\mathrm{k} \Omega$ |
| VCINH/VCOMP Division Ratio |  |  |  | 0.5 |  | V/V |
| VCOM Output Current Limit |  |  | 130 |  |  | mA |
| VCOM Offset Voltage |  |  | -8 |  | +8 | mV |
| VCOM Output Voltage Range |  |  | 1.5 |  | $\begin{gathered} \hline \mathrm{V}_{\mathrm{COMP}}- \\ 1.5 \mathrm{~V} \end{gathered}$ | V |
| VCOM DAC Step Size |  |  |  | 19.5 |  | mV |
| VCOM DAC Voltage Range |  |  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{COMP}} / \\ & 2 \pm 2.5 \mathrm{~V} \end{aligned}$ |  | V |

## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Electrical Characteristics (continued)

$\left(\mathrm{V}_{\text {INA }}=3.6 \mathrm{~V}\right.$, Limits are $100 \%$ tested at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ and $\mathrm{T}_{\mathrm{A}}=+105^{\circ} \mathrm{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested. $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{J}=-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| VCOM UndervoltageDetection Threshold |  | VCINH - VCOM, falling | -0.55 | -0.35 | -0.15 | V |
| VCOM OvervoltageDetection Threshold |  | VCINH - VCOM, rising | 0.04 | 0.25 | 0.41 | V |
| VCOM Fault Detection Filter Time |  | tfault[1:0] = 01 |  | 60 |  | ms |
| VCOM Discharge Resistance |  |  | 6 | 13 | 20 | k $\Omega$ |
| TFT FAULT PROTECTION |  |  |  |  |  |  |
| Fault Timeout |  | tfault[1:0] = 01 |  | 60 |  | ms |
| Fault Retry Time |  |  |  | 2.4 |  | s |
| FLTB Output Frequency |  | Stand-alone mode only | 0.88 | 1 | 1.12 | kHz |
| FLTB Output Duty Cycle, VGON or VGOFF Fault |  |  |  | 75 |  | \% |
| FLTB Output Duty Cycle, HVINP Fault |  |  |  | 50 |  | \% |
| FLTB Output Duty Cycle, AVDD Fault |  |  |  | 25 |  | \% |
| AVDD UndervoltageFault Threshold |  | Relative measurement between HVINP and AVDD | 70 | 75 | 80 | \% |
| FBP Short-Circuit Fault Threshold |  |  | 30 | 40 | 50 | \% |
| FBGH Short-Circuit Fault Threshold |  |  | 30 | 40 | 50 | \% |
| FBGL Short-Circuit Fault Threshold |  |  | 0.8 | 0.85 | 0.9 | V |
| Short-Circuit and Overload Fault Delay |  |  |  | 10 |  | $\mu \mathrm{s}$ |
| THERMAL PROTECTION |  |  |  |  |  |  |
| Thermal Shutdown | TSHDN |  |  | 165 |  | ${ }^{\circ} \mathrm{C}$ |
| Thermal-Shutdown Hysteresis | TSHDN_HYS |  |  | 15 |  | ${ }^{\circ} \mathrm{C}$ |
| LOGIC INPUT AND OUTPUTS |  |  |  |  |  |  |
| FLTB, DEL Low Output Voltage | V OL | $\mathrm{I}_{\text {SINK }}=5 \mathrm{~mA}$ |  |  | 0.4 | V |
| FLTB, DEL, SDA Leakage Current | IILEAK |  | -1 |  | +1 | $\mu \mathrm{A}$ |
| SDA Output Voltage Low | V OLSDA |  |  |  | 0.8 | V |
| ENP Pulldown Resistor Value | RENPPD |  | 50 | 75 |  | k $\Omega$ |

## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Electrical Characteristics (continued)

$\left(\mathrm{V}_{\text {INA }}=3.6 \mathrm{~V}\right.$, Limits are $100 \%$ tested at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ and $\mathrm{T}_{\mathrm{A}}=+105^{\circ} \mathrm{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested. $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{J}=-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ENP Glitch Filter Time | tenp |  |  | 10 |  | $\mu \mathrm{s}$ |
| ENP, CTL, SCL, SDA, ADD Input Voltage Low | VIL |  |  |  | 0.8 | V |
| ENP, CTL, SCL, SDA, ADD Input Voltage High | $\mathrm{V}_{\mathrm{IH}}$ |  | 2 |  |  | V |
| I2C INTERFACE |  |  |  |  |  |  |
| Clock Frequency | $\mathrm{f}_{\text {SCL }}$ |  |  |  | 400 | kHz |
| Setup Time (Repeated) START | tsu:STA |  | 260 |  |  | ns |
| Hold Time (Repeated) START | $t_{\text {thD }}$ STA |  | 260 |  |  | ns |
| SCL Low Time | tow |  | 350 |  |  | ns |
| SCL High Time | $\mathrm{t}_{\mathrm{HIGH}}$ |  | 260 |  |  | ns |
| Data Setup Time | $\mathrm{t}_{\text {SU:DAT }}$ |  | 50 |  |  | ns |
| Data Hold Time | $\mathrm{t}_{\mathrm{HD}: \text { DAT }}$ |  | 0 |  |  | ns |
| Setup Time for STOP Condition | tsu:sto |  | 260 |  |  | ns |
| Spike Suppression |  |  |  | 50 |  | ns |

Note 2: Note 1: Limits are $100 \%$ tested at $T_{A}=+25^{\circ} \mathrm{C}$. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization.

## Typical Operating Characteristics

$\left(\left(\mathrm{V}_{\text {INA }}=3.3 \mathrm{~V}, \mathrm{f}_{\mathrm{SW}}=2.2 \mathrm{MHz}, \mathrm{C}_{\mathrm{VCOM}}=1 \mu \mathrm{~F}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.\right.$ unless otherwise noted. $)$ )






## Typical Operating Characteristics (continued)

$\left(\left(\mathrm{V}_{\text {INA }}=3.3 \mathrm{~V}, \mathrm{f}_{\mathrm{SW}}=2.2 \mathrm{MHz}, \mathrm{C}_{\mathrm{VCOM}}=1 \mu \mathrm{~F}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.\right.$ unless otherwise noted. $)$ )


## Typical Operating Characteristics (continued)

$\left(\left(\mathrm{V}_{\text {INA }}=3.3 \mathrm{~V}, \mathrm{f}_{\mathrm{SW}}=2.2 \mathrm{MHz}, \mathrm{C}_{\mathrm{VCOM}}=1 \mu \mathrm{~F}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.\right.$ unless otherwise noted. $)$ )


## Typical Operating Characteristics (continued)

$\left(\left(\mathrm{V}_{\text {INA }}=3.3 \mathrm{~V}, \mathrm{f}_{\mathrm{SW}}=2.2 \mathrm{MHz}, \mathrm{C}_{\mathrm{VCOM}}=1 \mu \mathrm{~F}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.\right.$ unless otherwise noted. $\left.)\right)$




## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Pin Configuration

MAX20067


## Pin Description

| PIN | NAME | FUNCTION | REF <br> SUPPLY |
| :---: | :---: | :--- | :---: |
| 1 | FBGH | Positive Charge-Pump Feedback Connection. FBGH is regulated to 1.25V. <br> Connect a resistor-divider from VGON to GND with its midpoint connected to <br> FBGH. |  |
| 2 | FBGL | Negative Charge-Pump Feedback Connection. FBGL is regulated to 0.25V. <br> Connect a resistor-divider from REF to VGOFF with its midpoint connected to <br> FBGL. |  |
| 3 | GND | Ground Connection |  |
| 4 | VGOFF | Output of Negative Charge-Pump Block. |  |
| 5 | DRVN | Negative Charge-Pump Push-Pull Drive Output |  |
| 6 | VGON | Output of Positive Charge-Pump Block |  |
| 7 | DRVP | Positive Charge-Pump Push-Pull Drive Output |  |
| 8 | PGVDD | Supply voltage for positive charge-pump. PGVDD is connected to HVINP by <br> means of an internal switch when the positive charge-pump is enabled. Bypass <br> PGVDD with a ceramic capacitor of at least 1 $\mu$ F to GND. |  |

## Pin Description (continued)

| PIN | NAME | FUNCTION | $\begin{gathered} \text { REF } \\ \text { SUPPLY } \end{gathered}$ |
| :---: | :---: | :---: | :---: |
| 9 | BST | Bootstrap Capacitor Connection for Synchronous Rectifier Driver. Connect a $0.1 \mu \mathrm{~F}$ ceramic capacitor between BST and LXP. | HVINP |
| 10 | AVDD | Switched Output of Boost Converter. Connect a bypass capacitor of at least $4.7 \mu \mathrm{~F}$ from AVDD to PGND. |  |
| 11 | HVINP | Boost Output and Input to Positive and Negative Charge Pumps. Bypass HVINP with the boost-converter output capacitor placed close to the pin. |  |
| 12 | LXP | Switching Node of Boost Converter. Connect the boost inductor between LXP and INA. |  |
| 13 | PGND | Ground Connection for Boost Switching Device and VCOM Buffer. Connect to GND using a low-impedance trace. |  |
| 14 | SRC | Source of Internal High-Side Switch in Gate-Shading Circuit. SRC is usually connected to VGON. Bypass SRC with a $0.1 \mu \mathrm{~F}$ capacitor placed close to the pin. |  |
| 15 | GATES | Switched Output of Gate-Shading Circuit |  |
| 16 | DRN | Lower Input of Gate-Shading Circuit. Connect to an external source or GND through a discharge resistor. |  |
| 17 | VCOMP | Supply Voltage for VCOM Buffer. Normally connected to AVDD. Bypass $\mathrm{V}_{\text {COMP }}$ with a $0.1 \mu \mathrm{~F}$ ceramic capacitor placed close to the pin. |  |
| 18 | VCOM | Output of VCOM Amplifier. Bypass VCOM to GND with a $1 \mu \mathrm{~F}$ ceramic capacitor. |  |
| 19 | VCINH | Noninverting Input of VCOM Amplifier. In stand-alone mode, drive VCINH to set the VCOM output voltage. VCINH is prebiased to $50 \%$ of $\mathrm{V}_{\text {COMP }}$ with an internal resistor-divider comprising two $1 \mathrm{M} \Omega$ resistors. |  |
| 20 | INA | Supply Connection for Display Bias Circuitry. Bypass INA with a local $0.1 \mu \mathrm{~F}$ capacitor. |  |
| 21 | MODE | Mode Configuration Pin for Gate-Shading Level Shifter. MODE is used to adjust the timing of the gate-shading output. MODE is high impedance when connected to INA, and internally pulled down during UVLO or in shutdown. |  |
| 22 | CTL | Control Input for Gate-Shading Circuit. When CTL is high, the switch between GATES and SRC is on and the switch between GATES and DRN is off. When CTL is low, the switch between GATES and DRN is on and the switch between GATES and SRC is off. CTL is inhibited by $V_{C C}$ UVLO and when DEL is less than 1.25 V . |  |
| 23 | DEL | Gate-Shading Circuit Delay Input. Connect a capacitor from DEL to GND to set the turn-on delay. |  |
| 24 | SEQ | Logic-Level Sequencing Input Pin. The voltage level on SEQ determines whether the IC is serially controlled, or one of the predetermined sequences is used. Connect SEQ to INA or a resistive divider between INA and GND to set one of the preset stand-alone sequences (see Table 3). For serial control, connect SEQ to GND. |  |
| 25 | ENP | Active-High Enable Input for Boost Converter. ENP also enables the VGON and VGOFF regulators in the set sequence. ENP has an internal pulldown resistor. When serial control is used, connect ENP low. |  |
| 26 | DGND | Digital Ground. Connect directly to the exposed pad of the package. |  |
| 27 | ADD | $1^{2}$ C Address-Selection Pin. Connect to GND for a base address of $0 \times 20$, or to INA for a base address of $0 \times 28$. |  |
| 28 | SDA | Bidirectional ${ }^{2} \mathrm{C}$ C Data Pin |  |

## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Pin Description (continued)

| PIN | NAME | FUNCTION | REF <br> SUPPLY |
| :---: | :---: | :--- | :---: |
| 29 | SCL | Serial-Clock Input | Open-Drain, Active-Low Fault Output. Connect a pullup resistor from FLTB to a <br> logic supply $\leq 5 \mathrm{~V}$. In stand-alone mode, the duty cycle of the FLTB pin indicates <br> an error condition, if present (see Table 4). When the serial interface is used, <br> FLTB is either a 0 (indicating data to be read from the internal registers) or a 1. It <br> does not output a PWM signal. |
| 30 | FLTB |  |  |
| 31 | FBP | Boost Feedback Connection. FBP is regulated to 1.25V. Connect a resistor-divider <br> from HVINP to GND with its midpoint connected to FBP. |  |
| 32 | REF | Internal 1.25V Reference Output. Connect a 0.22 $\mu$ F capacitor from REF to GND. |  |
| - | EP | Exposed Pad. Connect EP to GND. |  |

## Functional Diagrams

Typical Application Circuit


## MAX20067/MAX20067B

Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Detailed Description

The MAX20067/MAX20067B are highly integrated power-supply ICs for automotive TFT-LCD applications. The ICs integrate one boost converter, two gate-driver supplies, a high-voltage "gate-shading" level shifter, and a high-current VCOM buffer.
The main power-supply section, comprising the boost converter and gate-driver supplies, operates from a 2.7 V to 5.5 V supply. The boost converter operates at 440 kHz or 2.2 MHz and has built-in spread spectrum that can be disabled using the serial interface for reducing EMI.
The boost converter provides an output voltage adjustable up to 18 V , with up to 200 mA output current and has two internal MOSFET switching elements.

The ICs provide gate-driver supplies using positive and negative charge-pump regulators, with a current capability of 10 mA for the positive charge pump (using a doubler charge pump) and 3 mA for the negative charge pump (assuming a 2 -stage charge pump). Output voltage is adjustable with $\mathrm{a}+32 \mathrm{~V}$ (max) output on the positive charge pump and -24 V on the negative charge pump.
The startup and shutdown sequences for all power domains, controlled using one of the preset modes, are selected using the SEQ pin. Sequencing can also be controlled through the serial interface when the SEQ pin is grounded.

## TFT Power Section

## Source-Driver Power Supplies

The source-driver power supply consists of a boost converter that generates +18 V (max) and can deliver up to +200 mA (+100mA for MAX20067B). The source-driver power supply's regulation voltage (HVINP) is set by a resistor-divider on FBP. The source driver uses constant-frequency peak-current-mode control, with internal fixed-slope compensation. Internal compensation stabilizes the control loop. At low output power, the converter enters skip mode.

The TFT boost converter has an internal error amplifier with a $g_{m}$ of $13 \mu S$ that has FBP and REF $=1.25 \mathrm{~V}$ as inputs. There is an internal compensation network at the output of the error amplifier as follows:

$$
\mathrm{C}_{\mathrm{C}}=140 \mathrm{pF}, \mathrm{R}_{\mathrm{C}}=500 \mathrm{k} \Omega
$$

For the current loop, there is internal current sensing using a transresistance of $R_{T}=0.21 \mathrm{~V} / \mathrm{A}$. The current-sense voltage $\left(\mathrm{V}_{\mathrm{CS}}=1 \_\right.$inductor $\left.\times \mathrm{R}_{\mathrm{T}}\right)$ is added to the slope compensation. The slope-compensation signal has a slope of 1250 mV per microsecond. The resulting $\mathrm{V}_{S U M}=\mathrm{V}_{\mathrm{CS}}+\mathrm{V}_{\text {SLOPE }}$ is compared to $\mathrm{V}_{\text {COMP }}$ (output of the error amplifier) at the input of the PWM comparator to regulate the LXP duty cycle.

## Gate-Driver Power Supplies

The positive gate-driver charge pump (VGON) generates +32 V (max) and the negative gate-driver charge pump (VGOFF) generates $-24 \mathrm{~V}(\mathrm{~min})$. The gate-driver supplies have a current capability of 10 mA for the positive charge pump (using a doubler charge pump) and 3 mA for the negative charge pump (assuming a 2 -stage charge pump). The VGON and VGOFF regulation voltages are both set using the external resistor networks, as shown in the Typical Application Circuit. Both charge-pump regulators use a 440 kHz switching frequency. The charge pumps regulate the output voltages by controlling the current that flows into the flying capacitors.

## Operation of the Positive Charge Pump

The positive charge-pump regulator is typically used to generate the positive supply rail for the TFT-LCD gate-driver ICs.
The output voltage is set with an external resistive voltage-divider from its output to GND, with the midpoint connected to FBGH. The number of charge-pump stages and the setting of the feedback-divider determine the output voltage of the positive charge-pump regulator. The charge pump push-pull output consists of a high-side p-channel MOSFET (P1) and a low-side n-channel MOSFET (N1) to control the power transfer.
The positive charge pump uses a simple skipping control scheme. The feedback signal (FBGH) is compared with a 1.25 V internal reference. The result of this comparison is sampled on every clock cycle. If the feedback signal is below 1.25 V ,

## MAX20067/MAX20067B

 Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interfacea DRVP cycle is initiated. In the first half period, the rising edge of the clock turns on N1 and turns off P1, allowing the flying capacitors to charge, while during the second half period, the falling edge of the clock turns off N1 allowing charge transfer to the output. During both phases, N1 and P1 act as current-limited switches with a current limit of at least 40 mA .

Alternatively, if the feedback signal is above 1.25 V at the clock rising edge, the regulator ignores the clock period and N 1 and P 1 remain off.
The charge-pump regulator also includes a discharge switch from VGON to ground, turned off to discharge the output capacitors during the sequential turn-off of the output voltages, as programmed by the SEQ pin or through $I^{2} \mathrm{C}$. The PGVDD node is internally connected through a switch to the HVINP voltage. See Table 3 for stand-alone sequencing options.

## Operation of the Negative Charge Pump

The negative charge-pump regulator is typically used to generate the negative supply rail for the TFT-LCD gate-driver ICs. The output voltage is set with an external resistive voltage-divider from its output to REF, with the midpoint connected to FBGL. The number of charge-pump stages and the setting of the feedback-divider determine the output of the negative charge-pump regulator. The charge-pump controller includes a high-side p-channel MOSFET (P1) and a low-side nchannel MOSFET (N1) to control the power transfer.
The feedback signal (FBGL) is compared with a 0.25 V internal reference obtained by partitioning the main 1.25 V reference. The result of this comparison is sampled on every clock cycle. If (REF - FBGL) is less than $1.25 \mathrm{~V}-0.25 \mathrm{~V}$ or 1 V , a DRVN cycle is initiated. In the first half period, the rising edge of the clock turns on P1 and turns off N1, allowing the flying capacitors to charge, while during the second half period, the falling edge of the clock turns on N1 and turns off P1 allowing charge transfer to the output. During both phases, N1 and P1 act as current-limited switches with a current limit of at least 15 mA .
Alternatively, if (REF - FBGL) is less than 1 V at the clock rising edge, the regulator ignores the clock period and N 1 and P1 remain off.
For sequencing of the output voltages at turn-off, a discharge switch is connected from VGOFF to ground. The desired sequence is programmable using the SEQ pin or through $I^{2}$ C. See Table 3 for the stand-alone sequencing options.

## Fault Protection on the TFT Section

The ICs have robust fault and overload protection. If any of the source-driver or gate-driver supplies fall below 80\% (typ) or above $115 \%$ of the programmed regulation voltage for more than 60 ms (typ, default), all the outputs turn off and a fault condition is set. If a short condition occurs on any of the source-driver supplies for more than $10 \mu \mathrm{~s}$, all the outputs turn off and a fault condition is set. A short condition is detected when the output voltage falls below $40 \%$ of the intended regulation voltage. The output with the fault turns off immediately, while the other outputs follow the turn-off sequence programmed by the SEQ pin or through $I^{2}$ C. The fault condition is cleared when the ENP pin or INA supply is cycled or after the retry timer ( 2.4 s typ, default) times out, if enabled. If needed, the retry time can be adjusted or this function disabled using the serial interface. In the case of a thermal fault, the ICs turn off immediately and remain off until the chip temperature drops by $15^{\circ} \mathrm{C}$ (typ).

## Output Control

The sequencing of the source-driver and gate-driver outputs (AVDD, VGON, and VGOFF) is determined by the setting of the SEQ pin or through $I^{2} \mathrm{C}$. All outputs are brought up with soft-start control to limit the inrush current. Table 3 lists the sequencing options using the SEQ pin.
The outputs are also turned off in sequence, with the boost converter the last block to be disabled. Active pulldowns are provided on all outputs to facilitate a controlled discharge. The pulldowns remain active for 512 ms after the boost has been disabled, at which point the ICs enter shutdown mode, if applicable.

## Power-Up/Power-Down Sequencing and Timing

The ICs allow for flexible power-up/power-down sequencing and timing of the source-driver and gate-driver power supplies (AVDD, VGON, and VGOFF). Toggling the ENP pin from low to high initiates an adjustable preset power-up sequence. Alternatively, power-up sequencing can be controlled through $I^{2} \mathrm{C}$. Toggling the ENP pin from high to low
initiates the power-down sequence. The ENP pin has an internal deglitching filter of $10 \mu \mathrm{~s}$ (typ). Note: A glitch in the ENP signal with a period less than $10 \mu$ s is ignored by the internal enable circuitry.

## Gate-Shading Level Shifter

The gate-shading level shifter is enabled when the soft-start of all regulators is completed and the DEL pin exceeds its enable threshold. A capacitor on the DEL pin can be used to adjust the startup-delay time together with the internal $5 \mu \mathrm{~A}$ current source. The delay can be calculated using the following equation:

$$
\text { Delay }=\frac{\left(1.25 \mathrm{~V} \times \mathrm{C}_{\mathrm{DEL}}\right)}{5 \mu \mathrm{~A}}
$$

When the ICs are disabled, GATES is discharged to GND. After the ICs are enabled, the GATES switches are off and GATES is high impedance until the complete power sequence is finished (without a fault occurring) and DEL exceeds 1.25 V . When DEL exceeds 1.25 V , the level shifter is activated and its state controlled by the CTL and MODE inputs according to Table 1. An external resistor and capacitor are used to produce the desired waveform where the rise of the output signal is fast, but the fall is an exponential decay controlled by the external values of the resistor and capacitor. In addition, a capacitor on the MODE pin can be used to delay the fall of the GATES output.
Connect MODE to INA when the $V_{G G S}$ delay is not needed. Connect a capacitor from MODE to GND to set the delay according to the following equation:

$$
C_{\mathrm{MODE}}=\frac{\left(100 \mu \mathrm{~A} \times t_{\mathrm{DMODE}}\right)}{1.75 \mathrm{~V}}
$$

where $t_{\text {DMODE }}$ is the desired delay if the level shifter is not used to connect CTL to GND.

## Table 1

Table 1. Gate-Shading Operating Modes

| CTL | MODE | GATES OUTPUT | CMODE DISCHARGE |
| :---: | :---: | :---: | :---: |
| Low | High | GATES shorted to DRN using internal device | - |
| High | High | GATES shorted to SRC using internal device | - |
| Low | Low | GATES shorted to DRN using internal device | Off |
| High | Low | GATES shorted to SRC using internal device | On |

## VCOM Buffer

The VCOM buffer is enabled when AVDD crosses its power-good threshold. The VCOM positive supply is $\mathrm{V}_{\text {COMP }}$, which is normally externally connected to the AVDD output, while its negative supply is ground. The output voltage is set by default to half of $\mathrm{V}_{\text {COMP }}$ through two $1000 \mathrm{k} \Omega$ internal resistors. The VCOM buffer can be controlled either by driving the VCINH pin or using the internal DAC that is written to through the serial interface. When driving the VCINH pin, the source impedance or the resistance of the external resistor-divider should be much lower than $500 \mathrm{k} \Omega$. In DAC mode, an 8-bit value is written through $I^{2} \mathrm{C}$, which sets the VCOM output voltage in a nominal range of $\pm 2.5 \mathrm{~V}$ around AVDD/ 2. Table 2 shows the correspondence between the DAC value written and the VCOM output voltage. The VCOM output can source or sink a current up to a peak of 130 mA . The LCD backplane consists of a distributed series capacitance and resistance, a load that can be easily driven by the buffer. In a short-circuit condition, the power dissipation of the VCOM buffer can lead to complete thermal shutdown of the ICs.
The VCOM buffer should be used with an external $1 \mu \mathrm{~F}$ ceramic capacitor connected from its output to GND.
A VCOM buffer fault is detected if the voltage difference between VCINH and the VCOM output pin is greater than 250 mV . The VCOM fault detection is filtered internally and a VCOM buffer fault is latched. To clear a fault, write a 0 to the corresponding fault bit. In stand-alone mode, toggle the ENP pin or power down the device and then power it on again.

## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

Table 2
Table 2. VCOM DAC Values

| DAC VALUE | NOMINAL VCOM OUTPUT VOLTAGE WITH V AVDD $^{\prime}=\mathbf{1 2 V}$ |
| :---: | :---: |
| $0 \times F F$ | 8.5 V |
| $0 \times F E$ | 8.5 V |
| $\ldots$ | $\ldots$ |
| $0 \times 80$ | 6.02 V |
| $0 \times 7 \mathrm{~F}$ | 6 V |
| $0 \times 7 \mathrm{E}$ | 5.98 V |
| $\ldots$ | $\ldots$ |
| $0 \times 01$ | 3.52 V |
| $0 \times 00$ | 3.5 V |

## FLTB Output

The FLTB output pin is an active-low, open-drain output that can be used to signal various device faults (for operation in stand-alone mode, see the Stand-Alone Mode section). When the $\mathrm{I}^{2} \mathrm{C}$ interface is used, the FLTB output can flag any or all of the following conditions:

- Overtemperature fault
- Overcurrent on AVDD
- Undervoltage on HVINP, VGON, or VGOFF
- Overvoltage on HVINP, VGON, or VGOFF
- VCOM overvoltage or undervoltage

Some of the above conditions can be masked from causing FLTB to go low by using the corresponding mask bit in the Fault Mask 1 (0x08) and Fault Mask 2 (0x09) registers.

## Stand-Alone Mode

The ICs can be used either in stand-alone mode (when there is no local microcontroller), or in $\mathrm{I}^{2} \mathrm{C}$ mode. In stand-alone mode, the SEQ pin sets the sequence according to Table 3.
The ENP pin (active high) is used to turn on or off the complete device. In stand-alone mode, the open-drain FLTB output is high when there is no detected fault. When a fault is detected, the FLTB pin outputs a signal with a duty cycle that indicates what type of fault has been detected. This is summarized in Table 4.

Table 3
Table 3. Output Sequencing

| NOMINAL SEQ PIN VOLTAGE | POWER-ON SEQUENCING |  |  | POWER-OFF SEQUENCING |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | 1st | 2nd | 3rd | 1st | 2nd | 3rd |  |
| GND | $1^{2} \mathrm{C}$ CONTROL |  |  |  |  |  |  |
| INA/2 | AVDD | VGOFF | VGON | VGON | VGOFF | AVDD |  |
| INA | AVDD | VGON | VGOFF | VGOFF | VGON | AVDD |  |

Table 4

## Table 4. FLTB Output Duty Cycle

| FLTB DUTY CYCLE | ERROR CONDITION |
| :---: | :---: |
| Continuously high | No error |
| $75 \%$ | VGON or VGOFF fault |

Table 4. FLTB Output Duty Cycle (continued)

| $50 \%$ | HVINP fault |
| :---: | :---: |
| $25 \%$ | AVDD fault |
| $1.5 \%$ | Thermal shutdown |

## I2C Serial Interface

The ICs contain an $I^{2} \mathrm{C}$ serial interface and act as slave devices. The basic unit of data transfer is 8 bits. To select ${ }^{2} \mathrm{C}$ mode, connect the SEQ pin to GND. The state of the SEQ pin is sampled when the INA voltage exceeds approximately 2 V and the status is latched.
Control of the power-up sequence through $I^{2} \mathrm{C}$ can be performed in two ways, manual or automatic. In manual mode, the $1^{2} \mathrm{C}$ host enables the outputs individually using the bits in the Regulator Control register (0x02). If a fault is detected in manual mode, the faulty output is disabled after the corresponding deglitch time and no other action is performed. Retry is disabled in manual mode.
The bits in Fault registers $0 \times 0 \mathrm{~A}$ and $0 \times 0 \mathrm{~B}$ can be cleared by writing a 0 to the corresponding position in the register. If the values of the other bits are retained, a 1 should be written to them. (e.g., if the vgon_ov bit is cleared in register $0 \times 0 \mathrm{~A}$, $0 \times 77$ should be written to the register). In this manner, only bit 3 is cleared, and the other bits are left unchanged.
In automatic mode, the sequence is preset using the autoseq_row1-autoseq_row3 and textd_dly 1 , textd_dly 2 bits, and executed using the autoseq_ctrl bit. See the Automatic Sequencing Mode section for further details.

## I2C Protocol

The $\mathrm{I}^{2} \mathrm{C}$ address is chosen by connecting the ADD pin to either GND or INA (see Table 5). A master device communicates with the IC by transmitting the correct Slave ID followed by the register address and data word. Each transmit sequence is framed by a START (S) or Repeated START (Sr) condition and a STOP (P) condition. Each word transmitted over the bus is 8 bits long and is always followed by an acknowledge clock pulse.
The SDA line operates as both an input and an open-drain output. A pullup resistor greater than $500 \Omega$ is required on the SDA bus, or the resistor has to be selected as a function of bus capacitance, such that the rise time on the bus is not greater than 120 ns per the $I^{2} \mathrm{C}$ bus specification. The SCL line operates as an input only. A pullup resistor greater than $500 \Omega$ is required on SCL if there are multiple masters on the bus, or if the master in a single-master system has an open-drain SCL output. In general, for the SCL line resistor selection, the same recommendations as the SDA line apply. Series resistors in line with SDA and SCL are optional. The SCL and SDA inputs suppress noise spikes to ensure proper device operation even on a noisy bus.

Table 5

## Table 5. $I^{2}$ C Slave Addresses

| ADD PIN CONNECTION | DEVICE ADDRESS |  |  |  |  |  | WRITE <br> ADDRESS | READ <br> ADDRESS |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | A6 | A5 | A4 | A3 | A2 | A1 |  | AD |  |
| GND | 0 | 1 | 0 | 0 | 0 | 0 | 0 | $0 \times 40$ | $0 \times 41$ |
| INA | 0 | 1 | 0 | 1 | 0 | 0 | 0 | $0 \times 50$ | $0 \times 51$ |

## Individual Output Control Through I2C

Using the bits in the Regulator Control register (0x02), all outputs can be controlled individually by the local host microcontroller. When using this mode of operation, a fault on any output is signaled by the FLTB output pin (if not masked) and the fault bits. The output with the fault remains active until the microcontroller intervenes.
When using the individual control bits, the boost converter must always be enabled first and disabled last in the sequence.

## Autosequencing Mode

In autosequencing mode, a complete sequence is configured using the autoseq_row1-3[2:0] and textd_dly1-2 bits and

## MAX20067/MAX20067B <br> Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $\mathrm{I}^{2} \mathrm{C}$ Interface

then executed by setting the autoseq_ctrl bit.
To use autosequencing, set the en_autoseq bit in the Configurations register ( $0 \times 01$ ) to 1 and then configure the desired sequence using the autoseq_row1-autoseq_row3 bits in the Auto Sequencing ctrl1 (0x04) and Auto Sequencing ctrl2 ( $0 x 05$ ) registers. The 3 bits of autoseq_row1 correspond to the AVDD output and each bit represents one of three time slots. To enable AVDD during the first time slot, set autoseq_row1 to 100. To enable AVDD during the second time slot, set autoseq_row1 to 010, etc. In an analogous fashion, autoseq_row2 sets the VGON time slot and autoseq_row3 sets the VGOFF time slot.

The delays between each of the time slots are configured using the textd_dly1 and textd_dly2 settings.
When the complete configuration is set, the sequence is executed automatically by setting autoseq_ctrl in the Regulator Control register ( $0 x 02$ ) to 1 . The corresponding power-off sequence can be performed by setting autoseq_ctrl to 0 . If a fault occurs in automatic mode, the faulty output is turned off and the other outputs are turned off in the set order. If retry is enabled, a retry is attempted after the appropriate delay.

Note: If the manual control bits have been used to enable one or more of the outputs, automatic sequencing behaves differently: it starts immediately when the en_autoseq bit is set.

Figure 1. Sample Sequence


## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Register Map

Register Map

| ADDRESS | NAME | MSB |  |  |  |  |  |  | LSB |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| bank 0 |  |  |  |  |  |  |  |  |  |
| $0 \times 00$ | Device Id[7:0] | rev_id[3:0] |  |  |  | dev_id[3:0] |  |  |  |
| $0 \times 01$ | Configurations[7:0] | $\begin{gathered} \text { fault_latc } \\ \text { h_dis } \end{gathered}$ | $\begin{aligned} & \text { en_autos } \\ & \text { eq } \end{aligned}$ | tretry[1:0] |  | tfault[1:0] |  | dis_ss | swfrq |
| $0 \times 02$ | Regulator control[7:0] | - | autoseq ctrl | $\begin{gathered} \text { dis_vco } \\ \text { m } \end{gathered}$ | dis_gs | en_vgoff | en_vgon | en_avdd | en_bst |
| $0 \times 03$ | Regulator power status[7:0] | - | - | vcom_on | gs_on | vgoff_on | vgon_on | avdd_on | bst_on |
| 0x04 | Auto sequencing ctr11[7:0] | - | - | autoseq_row2[2:0] |  |  | autoseq_row1[2:0] |  |  |
| $0 \times 05$ | Auto sequencing ctr12[7:0] | - | textd_dly2[1:0] |  | textd_dly1[1:0] |  | autoseq_row3[2:0] |  |  |
| $0 \times 06$ | VCOM voltage[7:0] | vcom_dac[7:0] |  |  |  |  |  |  |  |
| $0 \times 07$ | UNUSED - do not write to this register[7:0] | - | - | - | - | _ | - | - | - |
| $0 \times 08$ | Fault mask 1[7:0] | - | $\begin{gathered} \text { vgoff_uv } \\ \text { _mask } \end{gathered}$ | vgoff_ov _mask | $\begin{gathered} \text { vgon_uv } \\ \text { _mask } \end{gathered}$ | $\begin{gathered} \text { vgon_ov } \\ \text { _mask } \\ \hline \end{gathered}$ | avdd_ovl <br> d_mask | hvinp_uv _mask | hvinp_ov _mask |
| 0x09 | Fault mask 2[7:0] | - | - | - | $\begin{gathered} \text { vcom_uv } \\ \text { _mask } \end{gathered}$ | vcom_ov _mask | - | - | - |
| 0x0A | Fault register 1[7:0] | - | vgoff_uv | vgoff_ov | vgon_uv | vgon_ov | $\begin{gathered} \text { avdd_ovl } \\ \text { d } \end{gathered}$ | hvinp_uv | hvinp_ov |
| 0x0B | Fault register 2[7:0] | - | - | - | vcom_uv | vcom_ov | - | th_shdn | hw_rst |

## Register Details

## Device Id ( $0 \times 00$ )

Register to identify the device type and the revision number

| BIT | 7 | 6 | 4 | 3 | 2 | 1 | 0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | rev_id[3:0] |  |  | dev_id[3:0] |  |  |  |
| Reset | $0 \times 0$ |  |  | 0x9 |  |  |  |
| Access Type | Read Only |  |  | Read Only |  |  |  |


| BITFIELD | BITS | DESCRIPTION |
| :--- | :---: | :--- |
| rev_id | $7: 4$ | Revision ID. $0=$ revision 1, etc. |
| dev_id | $3: 0$ | Device ID. Reads 0x9. |

## Configurations ( $0 \times 01$ )

Miscellaneous configurations needed for part operations

| BIT | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | $\begin{aligned} & \text { fault_latch_ } \\ & \text { dis } \end{aligned}$ | en_autoseq | tretry[1:0] |  | tfault[1:0] |  | dis_ss | swfrq |
| Reset | 0x0 | $0 \times 0$ | 0x2 |  | 0x1 |  | $0 \times 0$ | 0x0 |
| Access Type | Write, Read | Write, Read | Write, Read |  | Write, Read |  | Write, Read | Write, Read |
| BITFIELD | BITS | DESCRIPTION |  |  | DECODE |  |  |  |
| $\begin{aligned} & \text { fault_latch_di } \\ & \text { s } \end{aligned}$ | 7 | Fault register control. When set to 0 , the fault register bits are latched. |  |  | 0x0: Fault register bits are latched fault flags $0 \times 1$ : Fault register bits are fault status bits (no latching) |  |  |  |
| en_autoseq | 6 | When set to 1, this bit enables the automatic sequencing feature. |  |  | $0 \times 0$ : Automatic sequencing is disabled $0 \times 1$ : Automatic sequencing is enabled |  |  |  |
| tretry | 5:4 | If retry is enabled (set to any value other than $0 \times 0$ ), then this is the time that elapses before a new power-on is attempted after turn-off due to a regulator fault. |  |  | $0 \times 0$ : Retry is disabled <br> $0 \times 1$ : Retry to power on regulator after 0.95s <br> $0 \times 2$ : Retry to power on regulator after 1.9 s <br> $0 \times 3$ : Retry to power on regulator after 3.8 s |  |  |  |
| tfault | 3:2 | Fault-deglitch duration. This is the time that a regulator fault must be continuously present before the fault is considered valid. |  |  | $0 \times 0$ : 30 ms <br> 0x1: 60ms <br> $0 \times 2: 120 \mathrm{~ms}$ <br> $0 \times 3$ : 250 ms |  |  |  |
| dis_ss | 1 | Boost spread-spectrum-disable control bit. |  |  | $0 \times 0$ : Boost spread spectrum enabled $0 \times 1$ : Boost spread spectrum disabled |  |  |  |
| swfrq | 0 | Boost converter switching-frequency selection. |  |  | $0 \times 0: 2.2 \mathrm{MHz}$ boost switching frequency $0 x 1$ : 440 kHz boost switching frequency |  |  |  |

## Regulator control (0x02)

Direct control of regulators enable. This register can be used on I2C variant when "en_autoseq $=0$ " to control the manual sequencing of regulators, i.e. regulators sequencing is completely controlled by host software. Note that some controls are implemented in this registers. As an example the enable of any regulator is not allowed unless "en_bst" has been enabled and ready (bst_on = 1 ).

| BIT | $\mathbf{7}$ | $\mathbf{6}$ | $\mathbf{5}$ | $\mathbf{4}$ | $\mathbf{3}$ | $\mathbf{2}$ | $\mathbf{1}$ | $\mathbf{0}$ |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | - | autoseq_ctrl | dis_vcom | dis_gs | en_vgoff | en_vgon | en_avdd | en_bst |
| Reset | - | $0 \times 0$ | $0 \times 0$ | $0 \times 0$ | $0 \times 0$ | $0 \times 0$ | $0 \times 0$ | $0 \times 0$ |
| Access <br> Type | - | Write, Read | Write, Read | Write, Read | Write, Read | Write, Read | Write, Read | Write, Read |
| BITFIELD | BITS | DESCRIPTION |  |  |  |  | DECODE |  |
|  |  | Controls the automatic sequencer. If the <br> automatic sequencer is enabled, setting this <br> bit to 1 starts the power-on sequence as <br> programmed. Deasserting this bit to 0 starts <br> the power-down sequence. Note that the <br> sequence programming cannot be altered <br> while the sequence is ongoing. Once the <br> current sequence is completed, sequence <br> programming is again enabled. If the <br> en_autoseq bit is set to 0, this bit has no <br> effect. | 0x0: If regulators are off, keep them as they are. If <br> regulators are on, start the power off sequence and <br> keep them off <br> 0x1: If regulators are off start the power on <br> sequence and keep them on. Else keep them as <br> they are. |  |  |  |  |  |
| autoseq_ctrl | 6 |  |  |  |  |  |  |  | Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface


| BITFIELD | BITS | DESCRIPTION | DECODE |
| :--- | :---: | :--- | :--- |
| dis_vcom | 5 | VCOM buffer disable. By default, the VCOM <br> buffer is enabled when the AVDD crosses its <br> power-good threshold. | 0x0: VCOM buffer is enabled <br> $0 \times 1:$ VCOM buffer has been disabled |
| dis_gs | 4 | Gate-shading disable. By default, the gate- <br> shading block is enabled when soft-start for <br> all regulators is completed and when the DEL <br> pin exceeds its enable threshold. | 0x0: Gate shading is enabled <br> $0 \times 1:$ Gate shading has been disabled |
| en_vgoff | 3 | Negative charge-pump enable. | 0x0: Negative charge pump is disabled <br> $0 \times 1:$ Negative charge pump has been enabled |
| en_vgon | 2 | Positive charge-pump enable. | 0x0: Positive charge pump is disabled <br> $0 \times 1:$ Positive charge pump has been enabled |
| en_avdd | 1 | Control bit for the switch between HVINP and <br> AVDD. Note that any attempt to set this bit to <br> 1 fails if the field "bst_ok" is 0. | $0 \times 0:$ Switch beween HVINP and AVDD is open <br> $0 \times 1:$ Switch beween HVINP and AVDD is closed |
| en_bst | 0 | Boost converter enable. | $0 \times 0:$ Buck is disabled <br> $0 \times 1: ~ B u c k ~ i s ~ e n a b l e d ~$ |

## Requlator power status ( $0 \times 03$ )

Status of the regulators. Each bit set to 1 means that related regulator is powered on (i.e. it has been enabled, the transient has completed and it's active ready)


## Auto sequencing ctrl1 ( $0 \times 04$ )

Programming for the control of the automatic sequncing

| BIT | $\mathbf{7}$ | $\mathbf{6}$ | $\mathbf{5}$ | $\mathbf{4}$ | $\mathbf{3}$ | $\mathbf{2}$ | $\mathbf{1}$ |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | - | - | autoseq_row2[2:0] | 0utoseq_row1[2:0] |  |  |  |
| Reset | - | - | $0 \times 0$ | $0 \times 0$ |  |  |  |
| Access <br> Type | - | - | Write, Read | Write, Read |  |  |  |


| BITFIELD | BITS | DESCRIPTION |
| :--- | :--- | :--- |
| autoseq_row2 | $5: 3$ | Autosequencing matrix row 2, corresponding to VGON. A 1 in this bit <br> corresponds to start the regulator in slot 1, 2, or 3 depending on the position <br> of the 1. If more than a 1 is present in the field, only the first one is considered <br> valid. |
| autoseq_row1 | Autosequencing matrix row 1, corresponding to AVDD. A 1 in this bit <br> corresponds to start the regulator in slot 1, 2, or 3 depending on the position <br> of the 1. If more than a 1 is present in the field, only the first one is considered <br> valid. |  |

## Auto sequencing ctrl2 (0x05)

Programming for the control of the automatic sequncing

| BIT | $\mathbf{7}$ | $\mathbf{6}$ | $\mathbf{5}$ | $\mathbf{4}$ | $\mathbf{3}$ | $\mathbf{2}$ | $\mathbf{1}$ |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | - | textd_dly2[1:0] | textd_dly1[1:0] | $\mathbf{0}$ |  |  |  |
| Reset | - | $0 \times 0$ | $0 \times 0$ | autoseq_row3[2:0] |  |  |  |
| Access <br> Type | - | Write, Read | Write, Read | $0 \times 0$ |  |  |  |


| BITFIELD | BITS | DESCRIPTION | DECODE |
| :---: | :---: | :---: | :---: |
| textd_dly2 | 6:5 | Delay extension as a percentage of the time that elapses between the power-on command for regulators in slot 2 and the assertion of the feedback signal that notifies they completed ramp up. If we name Tok such time the delay between slot 2 and slot 3 will be Tok x (1 + textd_dly2). | $0 \times 0$ : No delay after power OK of preceeding regulators <br> $0 \times 1$ : Additional $10 \%$ delay after power OK of preceeding regulators <br> 0x2: Additional 20\% delay after power OK of preceeding regulators <br> 0x3: Additional 30\% delay after power OK of preceeding regulators |
| textd_dly1 | 4:3 | Delay extension as a percentage of the time that elapses between the power-on command for regulators in slot 1 and the assertion of the feedback signal that notifies they completed ramp up. If we name Tok such time the delay between slot 1 and slot 2 will be Tok x ( $1+$ textd_dly1). | $0 \times 0$ : No delay after power OK of preceeding regulators <br> $0 \times 1$ : Additional $10 \%$ delay after power OK of preceeding regulators <br> 0x2: Additional 20\% delay after power OK of preceeding regulators <br> 0x3: Additional 30\% delay after power OK of preceeding regulators |
| autoseq_row 3 | 2:0 | Autosequencing matrix row 3, corresponding to VGOFF. A 1 in this bit corresponds to start the regulator in slot 1,2 , or 3 depending on the position of the 1 . If more than a 1 is present in the field, only the first one is considered valid. |  |

## VCOM voltage ( $0 \times 06$ )

This byte controls the setting of the DAC controlling the VCOM output voltage

| BIT | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | vcom_dac[7:0] |  |  |  |  |  |  |  |
| Reset | 0x7F |  |  |  |  |  |  |  |
| Access Type | Write, Read |  |  |  |  |  |  |  |


| BITFIELD | BITS | DESCRIPTION |
| :---: | :---: | :--- |
| vcom_dac | $7: 0$ | This byte controls the DAC that sets the VCOM output voltage. The output <br> step is 20mV/LSB. The mid-point is 0x7F = AVDD/2. |

## Fault mask 1 (0x08)

Fault mask register. Each bit in this register is able to mask the fault of the related bit. A 1 in a position enables the contribution of the fault flag to the FLTB assertion.


## Fault mask 2 ( $0 \times 09$ )

Fault mask register. Each bit in this register is able to mask the fault of the related bit. A 1 in a position enables the contribution of the fault flag to the FLTB assertion.

| BIT | $\mathbf{7}$ | $\mathbf{6}$ | $\mathbf{5}$ | $\mathbf{4}$ | $\mathbf{3}$ | $\mathbf{2}$ | $\mathbf{1}$ | $\mathbf{0}$ |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | - | - | - | vcom_uv_m <br> ask | vcom_ov_m <br> ask | - | - | - |
| Reset | - | - | - | $0 \times 0$ | $0 \times 0$ | - | - | - |
| Access <br> Type | - | - | - | Write, Read | Write, Read | - | - | - |


| BITFIELD | BITS | DESCRIPTION |
| :---: | :---: | :--- |
| vcom_uv_mask | 4 | Mask for VCOM undervoltage fault. If this bit is set to 1, an undervoltage fault <br> on VCOM does not cause FLTB to go low. |
| vcom_ov_mask | 3 | Mask for VCOM overvoltage fault. If this bit is set to 1, an overvoltage fault on <br> VCOM does not cause FLTB to go low. |

## Fault register $1(0 \times 0 A)$

Fault register 1. Each bit of this register can be a status bit (reflecting current status of the fault) or a flag bit (latched version of a status bit).

| BIT | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | - | vgoff_uv | vgoff_ov | vgon_uv | vgon_ov | avdd_ovld | hvinp_uv | hvinp_ov |
| Reset | - | $0 \times 0$ | 0x0 | 0x0 | $0 \times 0$ | 0x0 | 0x0 | 0x0 |
| Access Type | - | Write 0 to Clear, Read | Write 0 to Clear, Read | Write 0 to Clear, Read | Write 0 to Clear, Read | Write 0 to Clear, Read | Write 0 to Clear, Read | Write 0 to Clear, Read |
| BITFIELD | BITS | DESCRIPTION |  |  | DECODE |  |  |  |
| vgoff_uv | 6 | VGOFF undervoltage fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. |  |  | $0 \times 0$ : No fault is present or has happened $0 x 1$ : If "fault_latch_dis" $=0$ then a fault has happened or is still present. In this case the bit is CoR but reasserts if fault is still present. If "fault_latch_dis" = 1 then a fault is currently present else this bit is 0 . |  |  |  |
| vgoff_ov | 5 | VGOFF overvoltage fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. |  |  | $0 \times 0$ : No fault is present or has happened $0 \times 1$ : If "fault_latch_dis" $=0$ then a fault has happened or is still present. In this case the bit is CoR, but reasserts if fault is still present. If "fault_latch_dis" = 1 then a fault is currently present, else this bit is 0 . |  |  |  |
| vgon_uv | 4 | VGON undervoltage fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. |  |  | $0 \times 0$ : No fault is present or has happened $0 x 1$ : If "fault_latch_dis" $=0$ then a fault has happened or is still present. In this case the bit is CoR, but reasserts if fault is still present. If "fault_latch_dis" = 1 then a fault is currently present, else this bit is 0 . |  |  |  |
| vgon_ov | 3 | VGON overvoltage fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. |  |  | $0 \times 0$ : No fault is present or has happened $0 x 1$ : If "fault_latch_dis" $=0$ then a fault has happened or is still present. In this case the bit is CoR, but reasserts if fault is still present. If "fault_latch_dis" = 1 then a fault is currently present, else this bit is 0 . |  |  |  |
| avdd_ovld | 2 | AVDD overcurrent fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. |  |  | $0 \times 0$ : No fault is present or has happened $0 \times 1$ : If "fault_latch_dis" $=0$ then a fault has happened or is still present. In this case the bit is CoR, but reasserts if fault is still present. If "fault_latch_dis" = 1 then a fault is currently present, else this bit is 0 . |  |  |  |
| hvinp_uv | 1 | HVINP undervoltage fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. |  |  | $0 \times 0$ : No fault is present or has happened $0 x 1$ : If "fault_latch_dis" = 0 then a fault has happened or is still present. In this case the bit is CoR, but reasserts if fault is still present. If "fault_latch_dis" = 1 then a fault is currently present, else this bit is 0 . |  |  |  |

## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

| BITFIELD | BITS | DESCRIPTION | DECODE |
| :--- | :---: | :--- | :--- |
|  | 0 | HVINP overvoltage fault. Depending on <br> programing of "fault_latch_dis," this is a <br> status bit or a clear-on-read flag bit. | 0x0: No fault is present or has happened <br> Rvinp_ov |

## Fault register $2(0 \times 0 B)$

Fault register 2. Each bit of this register is a flag bit (latched fault).

| BIT | $\mathbf{7}$ | $\mathbf{6}$ | $\mathbf{5}$ | $\mathbf{4}$ | $\mathbf{3}$ | $\mathbf{2}$ | $\mathbf{1}$ | $\mathbf{0}$ |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Field | - | - | - | vcom_uv | vcom_ov | - | th_shdn | hw_rst |
| Reset | - | - | - | $0 \times 0$ | $0 \times 0$ | - | $0 \times 0$ | $0 \times 1$ |
| Access <br> Type | - | - | - | Write 0 to <br> Clear, Read | Write 0 to <br> Clear, Read | - | Write 0 to <br> Clear, Read | Read Only |


| BITFIELD | BITS | DESCRIPTION | DECODE |
| :---: | :---: | :---: | :---: |
| vcom_uv | 4 | VCOM buffer undervoltage fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. | $0 \times 0$ : No fault is present or has happened $0 \times 1$ : If "fault_latch_dis" $=0$ then a fault has happened or is still present. In this case the bit is CoR, but reasserts if fault is still present. If "fault_latch_dis" = 1 then a fault is currently present, else this bit is 0 . |
| vcom_ov | 3 | VCOM buffer overvoltage fault. Depending on programing of "fault_latch_dis," this is a status bit or a clear-on-read flag bit. | $0 \times 0$ : No fault is present or has happened $0 \times 1$ : If "fault_latch_dis" $=0$ then a fault has happened or is still present. In this case the bit is CoR, but reasserts if fault is still present. If "fault_latch_dis" $=1$ then a fault is currently present, else this bit is 0 . |
| th_shdn | 1 | Thermal-shutdown event was detected. If the event is still on, the flag reasserts upon CoR. | $0 \times 0$ : no thermal shutdown since last read $0 \times 1$ : Device is in thermal shutdown |
| hw_rst | 0 | Hardware reset event was detected | $0 \times 0$ : no POR since last read <br> $0 \times 1$ : this is the first read from the device after a POR |

## MAX20067/MAX20067B

Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Applications Information

## Boost Converter

## Inductor Selection

The value of the boost inductor is determined as follows:
$L=\frac{\left(V_{\text {INA }} \times D\right)}{\left(\operatorname{LIR} \times I_{\text {INA }} \times f_{S W}\right)}$
where $\mathrm{V}_{\text {INA }}$ is the boost input voltage, D is the duty cycle, LIR is the current ripple factor in the inductor (choose a value between 0.5 and 1 ), l INA is the boost converter input current, and $\mathrm{f}_{\mathrm{SW}}$ is either 2.2 MHz or 440 kHz .
Calculate the duty-cycle using:
$D=\frac{\left(1-\eta \times V_{\text {INA }}\right)}{V_{\text {OUT }}}$
where $\eta$ is the converter efficiency (assume 0.85 ) and $\mathrm{V}_{\text {OUT }}$ is the boost output voltage.
$I_{\mathrm{INA}}$, the average input current, can be estimated as follows:
$I_{\text {INA }}=\frac{\left(v_{\text {OUT }} \times I_{\text {OUT }}\right)}{\left(n \times v_{\text {INA }}\right)}$
where lout is the boost output current.

## Capacitor Selection

The input and output filter capacitors should be a low-ESR type (e.g., tantalum, ceramic, or low-ESR electrolytic) and should have RMS current ratings greater than:
$I_{\text {RMS }}=\frac{\left(\mathrm{LIR} \times I_{\text {INA }}\right)}{\sqrt{12}}$
for the input capacitor, and:
$I_{\text {RMS }}=I_{\text {OUT }} \times \sqrt{\frac{\left(D+\frac{\text { LIR }^{2}}{12}\right)}{(1-D)}}$
for the output capacitor. The output voltage contains a ripple component whose peak-to-peak value depends on the value of the ESR and capacitance of the output capacitor and is approximately the sum of two contributions:
$\Delta \mathrm{V}_{\text {RIPPLE }}=\Delta \mathrm{V}_{\mathrm{ESR}}+\Delta \mathrm{V}_{\text {CAP }}$
where:
$\Delta \mathrm{V}_{\mathrm{ESR}}=I_{\mathrm{INA}} \times\left(1+\frac{\mathrm{LIR}}{2}\right) \times R_{\mathrm{ESR}}$
and
$\Delta V_{\text {CAP }}=\frac{\left(I_{O U T} \times D\right)}{\left(c_{\text {OUT }} \times f_{S W}\right)}$
where $\mathrm{R}_{\mathrm{ESR}}$ is the ESR of the chosen output capacitor.

## Output-Voltage Selection

The output voltage of the boost converter can be adjusted using a resistive voltage-divider formed by $R_{\text {TOP }}$ and $R_{\text {BOTTOM }}$. Connect RTOP between HVINP and FBP, and connect RBOTTOM between FBP and GND. Select RBOTTOM in the $10 \mathrm{k} \Omega$ to $50 \mathrm{k} \Omega$ range. Calculate $\mathrm{R}_{\mathrm{TOP}}$ with the following equation:

$$
R_{\mathrm{TOP}}=R_{\mathrm{BOTTOM}} \times\left(\left(\frac{v_{\mathrm{OUT}}}{1.25}\right)-1\right)
$$

Place the resistors close to the device and connect $\mathrm{R}_{\text {BOTTOM }}$ to the analog ground plane.

## Boost Converter Operation at low INA and high Output Power

At high boost output power and low input voltages, the input current becomes high and and the boost converter's efficiency is lower. Under these conditions, it may be preferable to use the 440 kHz low-frequency setting. A further boost in efficiency at low input voltages can be obtained by adding a Schottky diode from LXP to HVINP. See all the relevant curve in the Typical Operating Characteristics section

## Charge-Pump Regulators

## Selecting the Number of Charge-Pump Stages

For highest efficiency, always choose the lowest number of charge-pump stages that meet the output voltage requirement. The number of positive charge-pump stages is given by:
$\mathrm{nPOS}=\frac{\mathrm{VGON}+V_{\text {DROPOUT }}-V_{\text {AVDD }}}{V_{\text {SUP }}-2 \times V_{D}}$
where nPOS is the number of positive charge-pump stages, VGON is the output of the positive charge-pump regulator, $\mathrm{V}_{\text {SUP }}$ is the supply voltage of the charge-pump regulators (HVINP), $\mathrm{V}_{\mathrm{D}}$ is the forward voltage drop of the charge-pump diodes, and $V_{\text {DROPOUT }}$ is the dropout margin for the regulator. Use $V_{\text {DROPOUT }}=600 \mathrm{mV}$.
The number of negative charge-pump stages is given by:
nNEG $=\frac{- \text { VGOFF }+V_{\text {DROPOUT }}}{V_{\text {SUP }}-2 \times V_{D}}$
where nNEG is the number of negative charge-pump stages and VGOFF is the output of the negative charge-pump regulator.

## Flying Capacitors

Increasing the flying capacitor (connected to DRVN and DRVP) value lowers the effective source impedance and increases the output current capability. Increasing the capacitance indefinitely, however, has a negligible effect on outputcurrent capability because the internal switch resistance and the diode impedance place a lower limit on the source impedance. A $0.1 \mu \mathrm{~F}$ ceramic capacitor works well in most applications. The flying capacitor's voltage rating must exceed the following:
VCX $>n \times V_{\text {HVINP }}$
where n is the stage number in which the flying capacitor appears.

## Charge-Pump Output Capacitor

Increasing the output capacitance or decreasing the ESR reduces the output ripple voltage and the peak-to-peak transient voltage. With ceramic capacitors, the output-voltage ripple is dominated by the capacitance value. Use the following equation to approximate the required capacitor value:
COUT_CP $>\frac{\text { LOAD_CP }^{2 x f}{ }^{\text {SW }} \times V_{\text {RIPPLE_CP }}}{}$
where COUT_CP $^{\prime}$ is the output capacitor of the charge pump, I IOAD_CP is the load current of the charge pump, $V_{\text {RIPPLE_CP }} \overline{\text { is }}$ the desired peak-to-peak value of the output ripple, and $f_{S W}^{-}$is the switching frequency, which is 440 kHz .

## MAX20067/MAX20067B

## Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

## Power Dissipation

The total internal power dissipation comprises five terms:

1. Boost converter power dissipation
2. Positive charge-pump dissipation
3. Negative charge-pump dissipation
4. Gate-shading power dissipation
5. VCOM buffer power dissipation

Items 2-4 are negligible, while the other terms can be estimated using:
$P_{\text {BOOST }}=I_{\text {INA }}^{2} \times R_{L} \times D+I_{\text {INA }} \times R_{H} \times(1-D)+0.5 \times I_{\text {INA }} \times V_{\text {HVINP }} \times t_{R F} \times f_{S W}$
where $R_{L}$ is the low-side LXP switch resistance, $R_{H}$ is the high-side $L X$ switch resistance, and $t_{R F}$ is the LXP rise/fall time that can be approximated by 5 ns :
$P_{\mathrm{VCOM}}=\left(V_{\mathrm{AVDD}}-V_{\mathrm{VCOM}}\right)^{*} /_{\text {VCOM }}$
where $\mathrm{I}_{\mathrm{VCOM}}$ is the RMS VCOM buffer output current.

## PCB Layout Example

Figure 2 shows an example for the layout of the power components around the MAX20067/MAX20067B. This layout minimizes the area of the LXP node and the area of the switching current loop. Follow these guidelines for the rest of the layout:

1. Separate power and analog grounds on the board and connect them together at a single point.
2. Connect all feedback resistor-dividers to the analog or "quiet" ground, along with the REF and INA capacitors. Feedback resistors should be placed close to their associated pins to avoid noise pickup.
3. Place decoupling capacitors as close as possible to their respective pins.
4. Keep high-current paths as short and wide as possible.
5. Route high-speed switching nodes (i.e., LXP, DRVN, and DRVP) away from sensitive analog nodes (i.e., FBP, FBGH, FBGL, and REF).

Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $\mathrm{I}^{2} \mathrm{C}$ Interface

## Layout Example



Figure 1. Layout Example

## MAX20067/MAX20067B Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface

 <br> <br> Automotive 3-Channel Display Bias IC with VCOM} <br> <br> Automotive 3-Channel Display Bias IC with VCOM}
## Ordering Information

| PART | TEMP RANGE | PIN-PACKAGE | PKG CODE |
| :--- | :---: | :---: | :---: |
| MAX20067GTJ/V+ | $-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$ | 32 TQFN | T3255 +4 C |
| MAX20067BGTJ/V+ | $-40^{\circ} \mathrm{C}$ to $+105^{\circ} \mathrm{C}$ | 32 TQFN | T3255 +4 C |

$N$ denotes an automotive qualified part.
+Denotes a lead(Pb)-free/RoHS-compliant package.

# Automotive 3-Channel Display Bias IC with VCOM Buffer, Level Shifter, and $I^{2} \mathrm{C}$ Interface 

## Revision History

| REVISION <br> NUMBER | REVISION <br> DATE | DESCRIPTION | PAGES <br> CHANGED |
| :---: | :---: | :--- | :---: |
| 0 | $7 / 17$ | Initial release | - |
| 1 | $9 / 20$ | Added MAX20067B variant, adjusted VGON, SRC and DRN absolute maximum <br> ratings and operating voltage ranges. | $1,3,4,5,6,16$ |
| 2 | $1 / 21$ | Changed maximum value of VGOFF Output Voltage Range to -4V, adjusted VGON, <br> SRC and DRN absolute maximum ratings and operating voltage ranges. | $1,3,4,5,6,16$ |

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